



Thunder High Power Products

Silicon N-Channel Planar Power MOSFET

Description

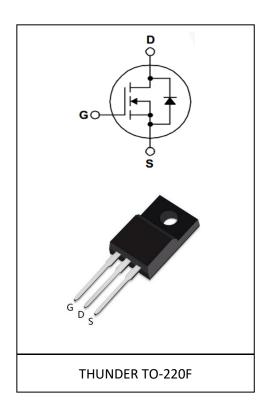
The TH5N100PF utilizes the latest processing techniques to achieve low on-resistance per silicon area. Additional features of this MOSFET are 150° C operating junction temperature and high repetitive peak current capability. These features combine to make this MOSFET a highly efficient, robust and reliable device for PDP driving applications. It can be used in a wide variety of applications.

General Features

- ●V_{DS}=1000V,I_D=5A
- •Low ON Resistance, $R_{DS(ON)} = 2.2\Omega@V_{GS} = 10V$, $I_D = 2.5A$
- •Low reverse transfer capacitance
- ●Low Qg for fast response
- Short fall & rise times for fast switching
- ●100% single pulse avalanche energy Test

Application

- Power switching application
- Digital amplifier
- Adapter and charger



Product Summary

V_{DS}	1000V
R _{DS(on)}	2.2Ω
I _D	5A

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Drain-source voltage	V _{DS}	1000	V
Continuous drain current T _C = 25°C (Silicon limit)	I _D	5	А
Pulsed drain current ($T_C = 25$ °C, t_p limited by T_{jmax})	I _{DM}	20	Α
Avalanche energy, single pulse (L=10mH, Rg=25Ω)	E _{AS}	450	mJ
Gate-Source voltage	V_{GS}	±30	V
Power dissipation ($T_C = 25^{\circ}C$)	P _D	125	W
Operating junction and storage temperature	$T_{j}T_{stg}$	-55+150	°C



Thermal Resistance

Parameter	Symbol	Max	Unit
Thermal resistance, junction – case.	R_thJC	1.0	°C/W
Thermal resistance, junction – ambient(min. footprint)	RthJA	62	C/VV

Electrical Characteristic (at Tj = 25 °C, unless otherwise specified)

Davamatar	Cumbal		Value		Unit	Test Condition
Parameter	Symbol	min.	typ.	max.	Unit	rest Condition

Static Characteristic

Drain-source breakdown voltage	BV _{DSS}	1000	-	-	V	V _{GS} =0V,I _D =250uA
Gate threshold voltage	$V_{GS(th)}$	3.0	-	5.0	٧	$V_{DS}=V_{GS}, I_{D}=250uA$
Zoro goto voltago drain		-	-	1	μA	V_{DS} =1000V, V_{GS} =0V T_j =25 °C
Zero gate voltage drain current	I _{DSS}	-	-	10	μA	V_{DS} =800V, V_{GS} =0V T_{j} =125 °C
Gate-source leakage current	I _{GSS}	-	-	±100	nA	V _{GS} =±30V, V _{DS} =0V
Drain-source on-state resistance	R _{DS(on)}	-	2.2	2.5	mΩ	V _{GS} =10V, I _D =2.5A

Dynamic Characteristic

Input Capacitance	C _{iss}	-	1470	-		
Output Capacitance	C _{oss}	-	21	-	рF	$V_{GS}=0V, V_{DS}=25V$
Reverse Transfer Capacitance	C _{rss}	-	115	-	ļ .	f=1MHz
Gate Total Charge	Qg	-	36	-		
Gate-Source charge	Q_{gs}	-	7.5	-	nC	V _{GS} =10V, V _{DS} =800V I _D =5A
Gate-Drain charge	Q_{gd}	-	14	-		1 _D -370
Turn-on delay time	t _{d(on)}	-	20	-		
Rise time	t _r	-	23	-		V _{DD} =500V, I _D =5A
Turn-off delay time	t _{d(off)}	-	28	-	ns	$R_G = 25 \Omega$
Fall time	t _f	-	26	-		





Body Diode Characteristic

Parameter	Symbol	Value			Unit	Test Condition
	Symbol	min.	typ.	max.	Onit	rest Condition
Body Diode Forward Voltage	V_{SD}	-	-	1.5	V	V _{GS} =0 V, I _{DS} =5 A
Body Diode Continuous Forward Current	Is	-	-	5	Α	Tc=25°C
Body Diode Reverse Recovery Time	t _{rr}	-	320	-	ns	T _C =25°C,I _S =5A
Body Diode Reverse Recovery Charge	Q _{rr}	-	1	-	μC	di/dt=100A/us

Typical Performance Characteristics

Fig 1: Output Characteristics

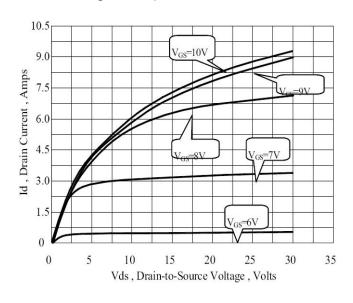


Fig 2: Transfer Characteristics

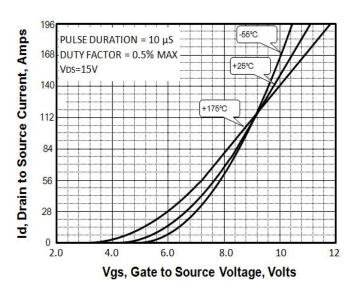


Fig 3: Rds(on) vs. Temperature

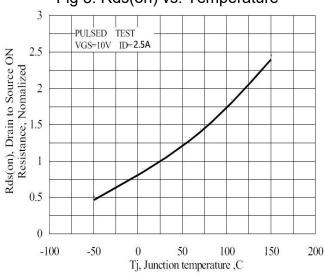
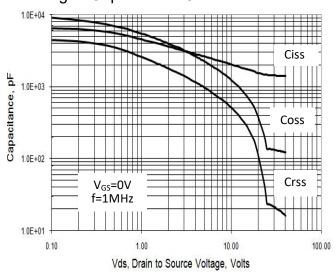


Fig 4: Capacitance Characteristics



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Fig 5: Gate Charge Characteristics

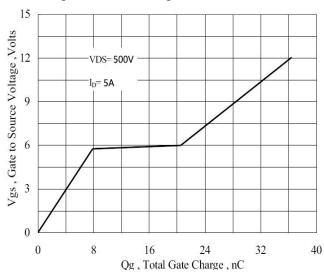


Fig 7: Power Dissipation

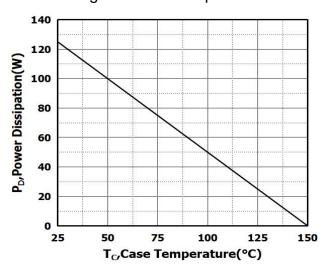


Fig 9: Safe Operating Area

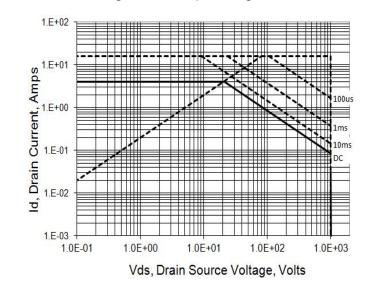


Fig 6: Body Diode Transfer Characteristics

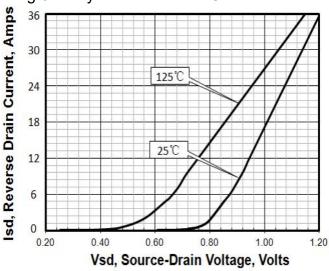


Fig 8: Drain Current Derating

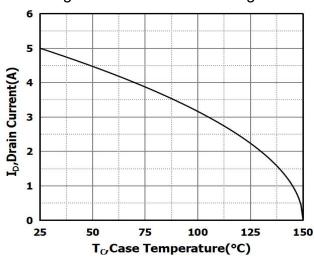
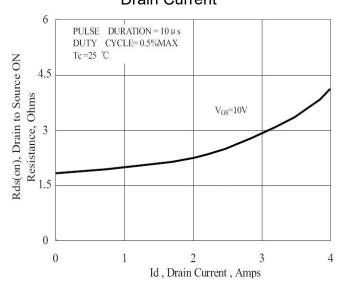


Fig 10: Drain to Source ON Resistance vs

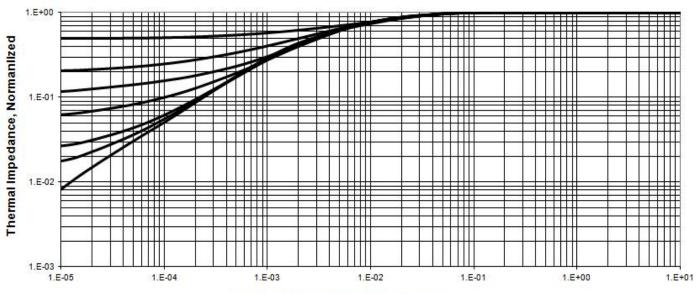
Drain Current



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Fig 11:Transient Thermal Response Curve



Rectangular Pulse Duration, Seconds

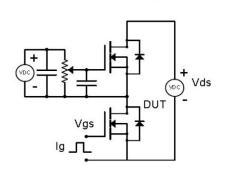
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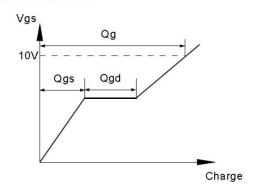




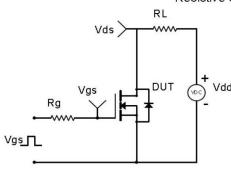
Test Circuit & Waveform

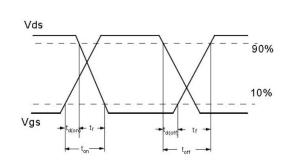
Gate Charge Test Circuit & Waveform



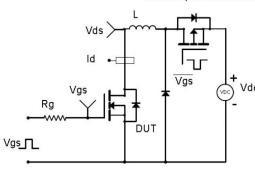


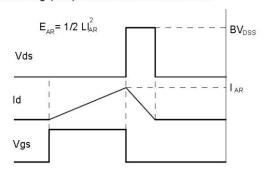
Resistive Switching Test Circuit & Waveforms



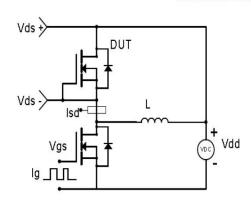


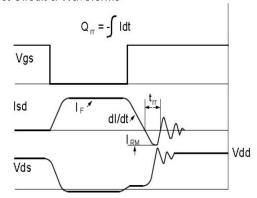
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms





Diode Recovery Test Circuit & Waveforms





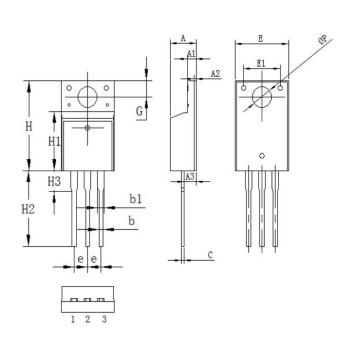




Package Information

TO-220F PACKAGE





0 1 1	单位 mm						
Symbol	Min	Nom	Max				
A	4. 55	4. 7 <mark>5</mark>	4. 95				
A1	2. 40	2. 60	2. 80				
A2	0.40	0.60	0.80				
A3	2. 10	2. 30	2. 50				
b1	1. 10	1.30	1. 50				
b	0.60	0.80	1.00				
С	0.42 0.50		0. 58				
е	2. 30	2. 50	2. 70				
Е	9. 9	10.1	10. 3				
E1	6.8	7	7. 2				
Н	15.8 16.0		16. 2				
H1	9. 10 9. 30		9. 50				
H2	12.5 13.0		13. 5				
НЗ	3. 10	3. 30	3. 50				
G	3. 00	3. 20	3. 40				
ФР	3.00	3. 20	3. 40				

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